

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/757,276
Filing Date January 14, 2004
Inventor.....Kevin Beaman
Assignee..... Micron Technology, Inc.
Group Art Unit..... 2813
Examiner Stephen Smoot
Attorney's Docket No. MI22-2475
Customer No. 021567
Title: Semiconductor Assemblies, Methods of Forming Structures over Semiconductor
Substrates, and Methods of Forming Transistors Associated with Semiconductor
Substrates

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT


Reference - - See attached Form PTO-1449

The attached Form PTO-1449 is submitted in compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the references listed on the attached Form PTO-1449. Pursuant to Federal Register Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art references, if any, are attached. No admission is made regarding whether the submitted references are prior art.

Citation of this reference is respectfully requested.

Respectfully submitted,

Date: 6-20-07



D. Brent Kenady
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2475	SERIAL NO. 10/757,276	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Kevin L. Beaman		
					FILING DATE January 14, 2004	GROUP 2813	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,015,739	1/18/2000	Gardner et al.			
	AB	6,057,584	5/2/2000	Gardner et al.			
	AC	6,649,538	11/18/2003	Cheng et al.			
	AD	2002/0094621 A1	7/2002	Sandhu et al.			
	AE	2002/0094620 A1	7/2002	Sandhu et al.			
	AF	2002/0098710 A1	7/2002	Sandhu et al.			
	AG	2002/0182812 A1	12/2002	Sandhu et al.			
	AH	2005/0087820 A1	4/28/2005	Bai et al.			
	AI	2006/0134864 A1	6/22/2006	Higashitani et al.			
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
EXAMINER				DATE CONSIDERED			
<p>*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							